



Politechnika Wroclawska

**Specimen Preparation
for SEM
investigation**

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Presentation program

- Aim of SEM investigation
- Investigated materials
- Condition for specimens
- Preparation
- Specimen fixation
- Replica
- Examples



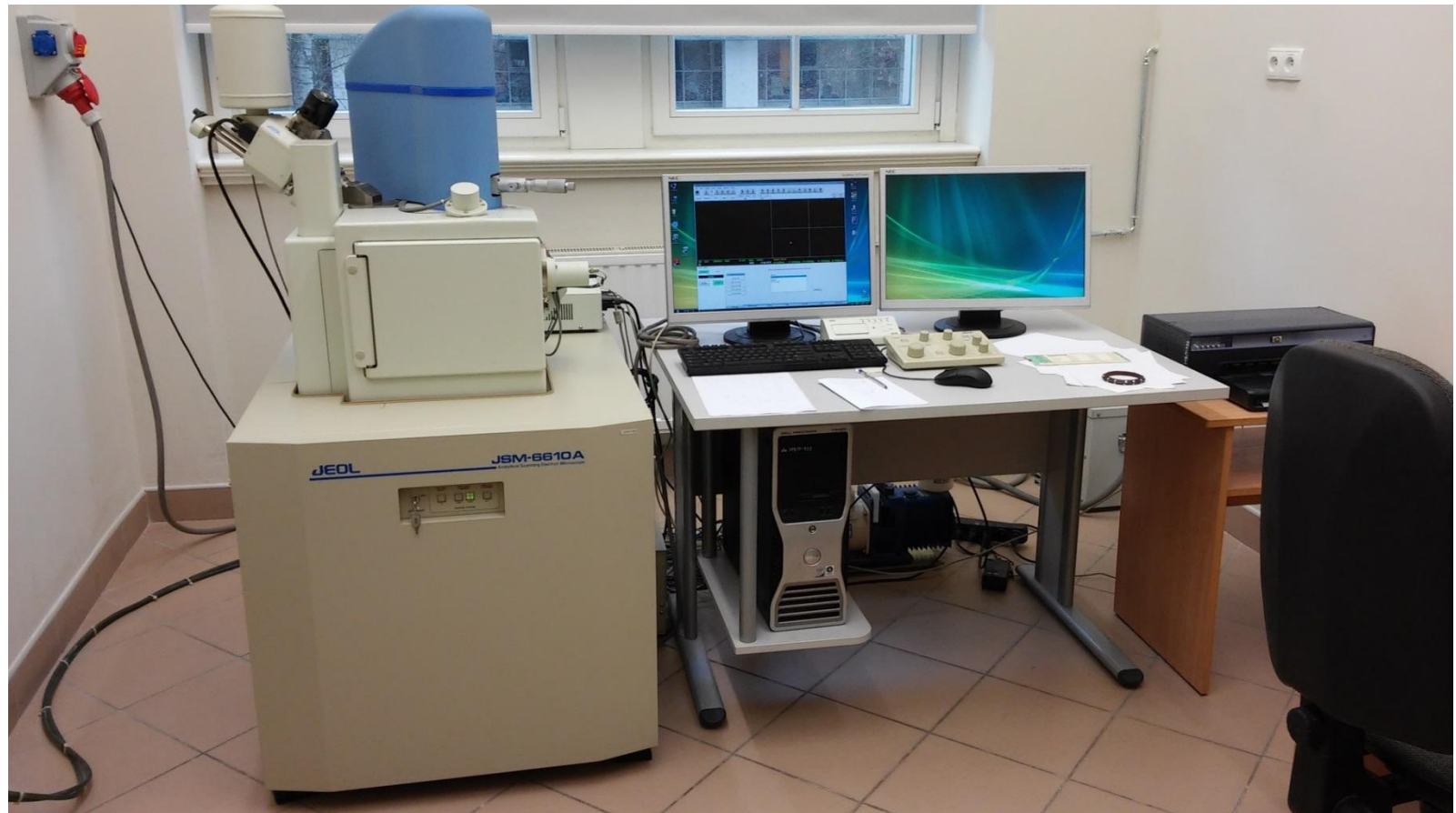
Aim of SEM investigation

Materials are investigated for:

- Mikrostructure determination (SE, BSE, AE, EBSD - Electron Beam Selected Diffraction)
- Chemical composition: (EDS, BSE, AE)



Analytical SEM JEOL JSM-6610A





Low vacuum SEM JSM- 5800LV





Types of specimens for SEM investigation

Four types of specimens:

1. Metallic
2. Polymer
3. Biological
4. Geological



Metallic specimens

For current conductive metallic specimens any additional preparation is not necessary.

They can be investigated like specimens for macro or metallography research.

Specimen can be at polished or to be at etched state.

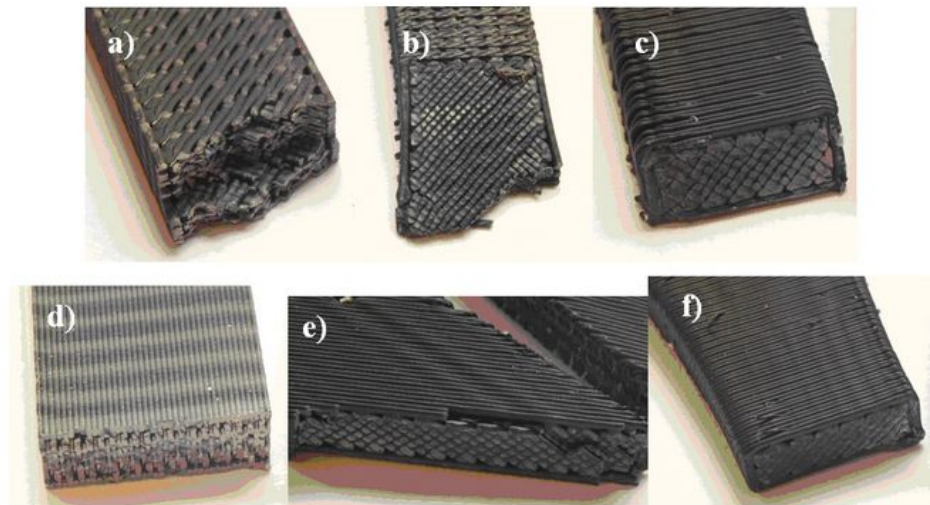
It is only necessary to fix the specimen with appropriate holder.





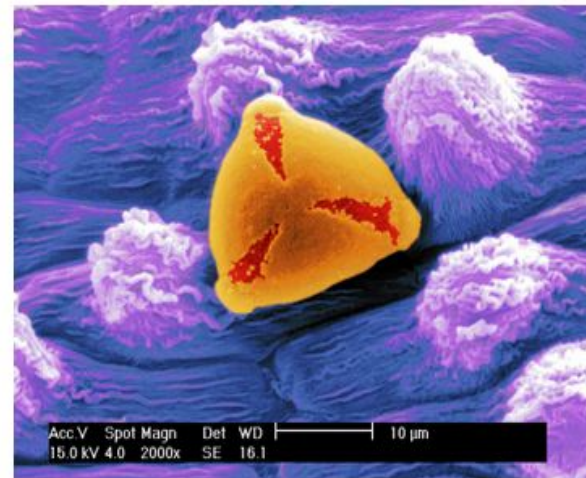
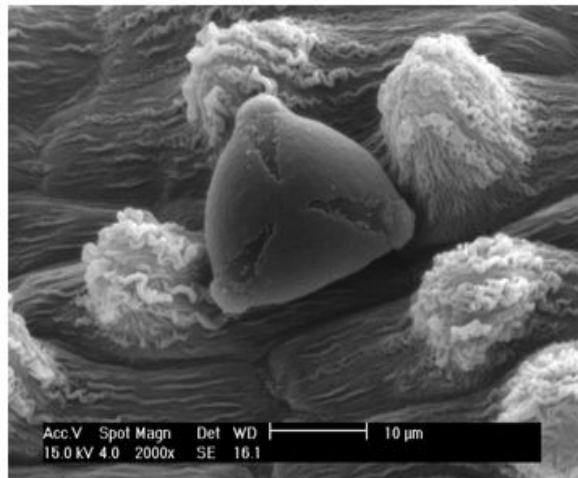
Specimens from polymers and composites

Polymer specimens must be sputtered by the layer of current conductive elements like: C, Au, Pt, Cu.



Biological specimens

Living cells, biological tissue, and some organs need to be specially prepared for the reason their fixation and protection to stabilize them and to protect against the ravages of the electron beam.



SEM image of pollen before and after graphic processing



Biological specimens

Biological specimens must be:

1. Dried, because inside the SEM chamber the material will be in the vacuum and therefore cannot be inserted preparations hydrated.
2. Sputered by current conductive material. Carbon is the best.



Flower petals sprinkled by gold





Samples of powder sputtered by gold





Biological specimens covered by gold



Specimen size

Specime sizes are limited by dimensions of SEM support table. Typical values are:

- Diameter below 5cm,
- Highest below 2,5cm.

Typical dimensions are: 10 x 10 x 5 mm.





Specimens embedding

Specimens are embedded at epoxy resin for the reason of better mounting and correction of specimen quality.

Before mounting specimens must be cleaned, free of dust, grease and any impurities.

Two techniques can be applied:

- Hot embedding under the pressure,
- Cold embedding.



Specimen embedding

- „Cold embedding” is suitable for materials sensitive at high temperature and pressure. Special epoxy or acrylic resins are applied.
- „Hot embedding” is suitable in the case when high quality of specimen preparation, equal size, shape and short time preparation is necessary. This process is realized by special equipment, (hot temperature press pressure).





Electrical current conductivity

Specimens analyzed by SEM methods must conduct electrical current.

If specimen doesn't conduct electrical current, then must be covered by the layer of Au, Pt, C or Cu.

Such prepared specimens can be investigated at high or low vacuum.



Specimen preparation

- Cutting, to obtain dimensions limited by support table disposed inside specimen chamber
- Cleaning and degreasing of specimen surfaces
- Grinding
- Polishing
- Etching



Specimen preparation

Grinding, by using special waterproof fine grain grinding papers.





Specimen preparation

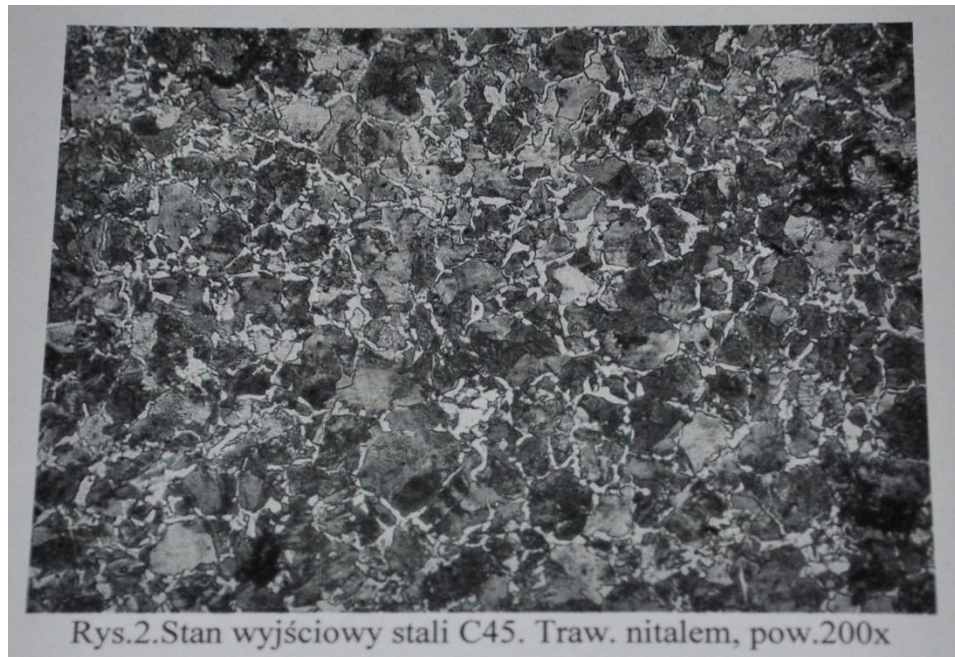
Mechanical polishing by using special velvet tissue immersed by diamant paste or water suspension of Al₂O₃. Any traces of scratches must be eliminated. Specimen surface must be brilliant.





Specimen preparation

Etching is the last operation necessary for microstructure visualisation. It is realised by application chemical reagent on the surface of polished specimen.





Etching reagents

Rodzaj stopu	Skład odczynnika	Sposób trawienia	Zastosowanie
Stopy Fe-C	Nital - $Mi_{10}Fe$ 1- 5cm ³ HNO ₃ + 100 cm ³ alkoholu etylowego	Kilka sekund do kilku minut w zależności od rodzaju i stopu	Ujawnia granice ziaren i składniki strukturalne stopów
Stopy Fe-C	Pikral - $Mi_{13}Fe$ 2-5 cm ³ kwasu pikrynowego + 100 cm ³ alkoholu etylowego	Kilka sekund do kilku minut w zależności od rodzaju stopu	jw.
Stale węglowe i niskostopowe	Zasado wypikrynian sodu – $Mi_{10}Fe$ 25 g NaOH + 2 g kwasu pikrynowego + 75 g H ₂ O	Temp. 60~100°C, kilka do kilkunastu minut	Zabarwia na brązowy kolor cementyt i azotki żelaza-feryt pozostawia jasny
Stale węglowe i stopowe do ulepszenia	$Mi_{17}Fe$ 5 cm ³ kwasu pikrynowego + 0,5% alkilodisulfonianu sodu (teepol) + 100 cm ³ H ₂ O	Temp. ok. 55°C, czas traw. 1 - 3 min	Ujawnia granice ziaren austenitu w stalach zahartowanych i odpuszczonych
Stale stopowe chromowe i szybko tnące	$Mi_{13}Fe$ 10 g żelazicyjanku potasu + 10 g wodorotlenku potasu + 100 ml H ₂ O	W temp. pokojowej	Do stali stopowych narzędziowych. Trawi węgliki stopowe. Do stali 18-8. Trawi wysokotemperaturowy ferryt



Etching reagents

Stopy miedzi	Mi23Cu 100 g nadsiarczanu amonowego +1 dm ³ wody	Trawienie na zimno lub w 60°C, płukanie wodą lub alkoholem	Ujawnia granice ziaren
Stopy aluminium	Mi1Al 0,5 cm ³ HF (1,13) ++ 99,5 cm ³ H ₂ O	Temp. 20°C, płukanie wodą lub alkoholem	Ujawnia granice ziaren i fazy międzymetaliczne
Stopy aluminium	Mi7Al 1 g NaOH + 100 cm ³ H ₂ O	Temp. 50°C, czas 5 - 180 s płukanie 5% HNO ₃ i wodą lub alkoholem	Ujawnia fazy między- metaliczne w stopach z Cu, Ni
Do cynku	Ni35Zn 5 cm ³ HNO ₃ (1,4) + +95 cm ³ alkoholu etylowego	Temp. 20°C, płukanie alkoholem	Ujawnia granice ziaren
Do cyny i stopów	Mi38Sn 15 cm ³ HNO ₃ (1,4) + +95 cm ³ alkoholu etylowego	Temp. 20°C, płukanie alkoholem	Ujawnia granice ziaren. Wytrawia fazy bogate w Pb
Do ołowiu i stopów	Mi42Pb 5 cm ³ kwasu octowego lodowatego +95 cm ³ alkoholu etylowego	Temp. 20°C, płukanie alkoholem	Ujawnia granice ziaren i struktury pierwotnej w stopach z Sb



Cross Section Polisher SM-09010

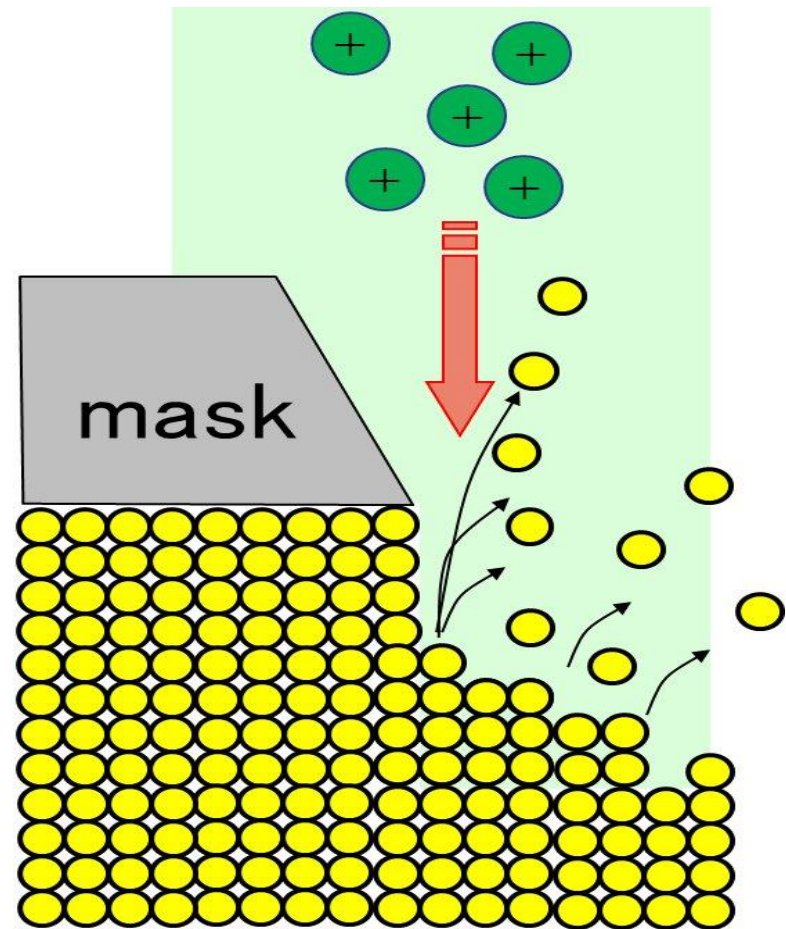
Cross Section Polisher,
makes cross section
perpendicular to the
specimen surface.
It is suitable for investigation
of multilayer structures.





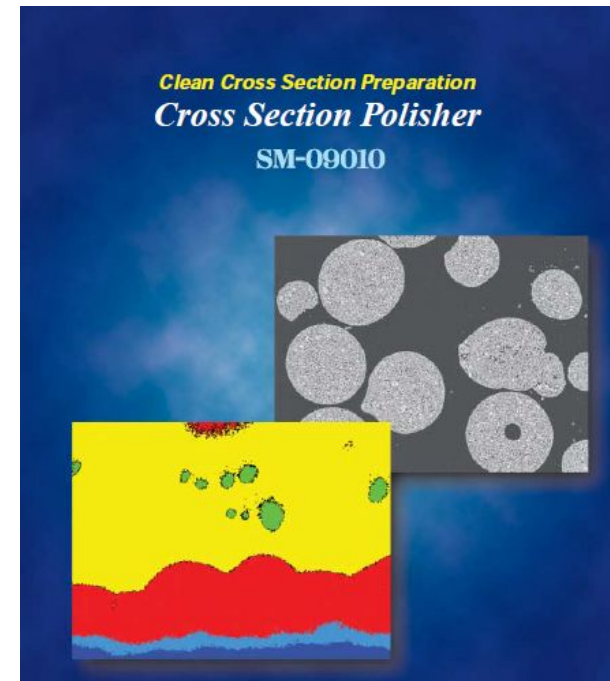
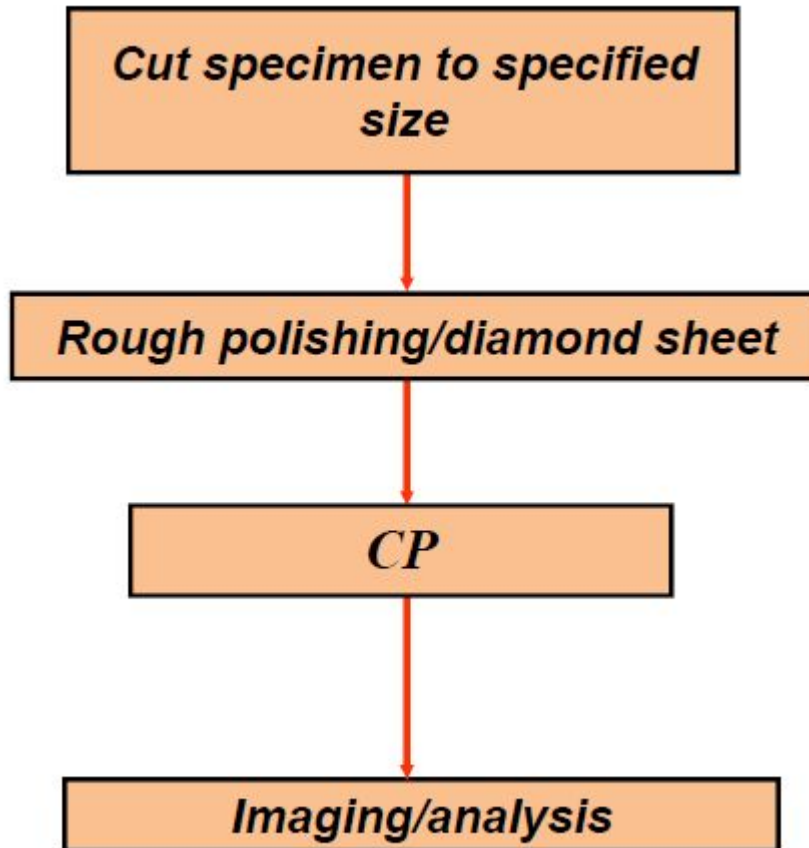
Cross Section Polisher SM-09010

Principle of operation





Procedura przygotowania próbki





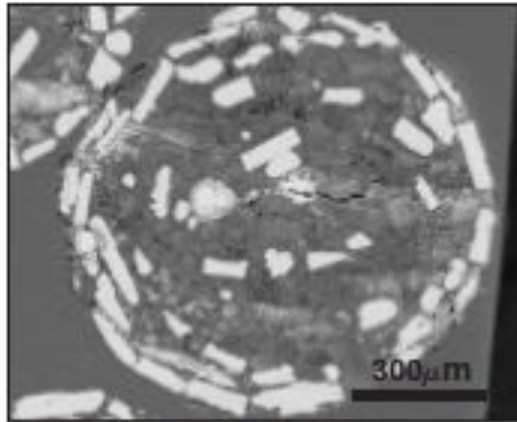
Specimens cutting

Saw equipment for sample
precision cutting

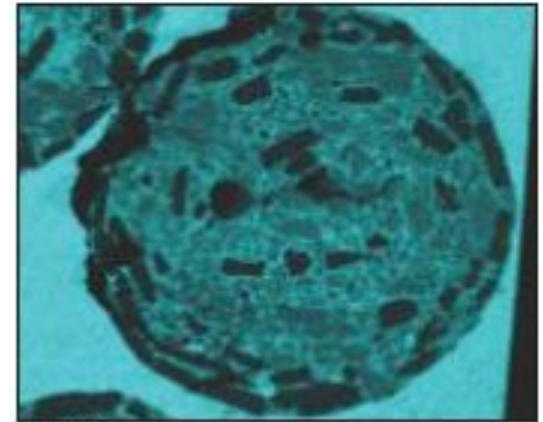


Examples of SEM application

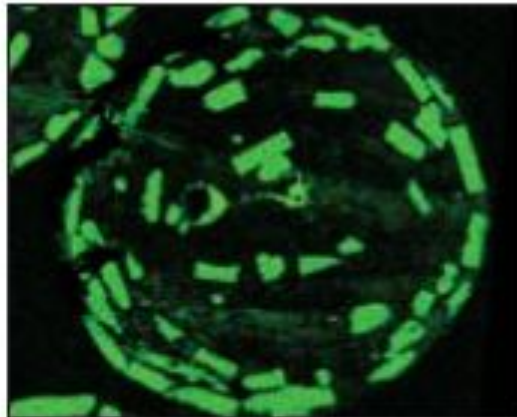
Granulated medicine



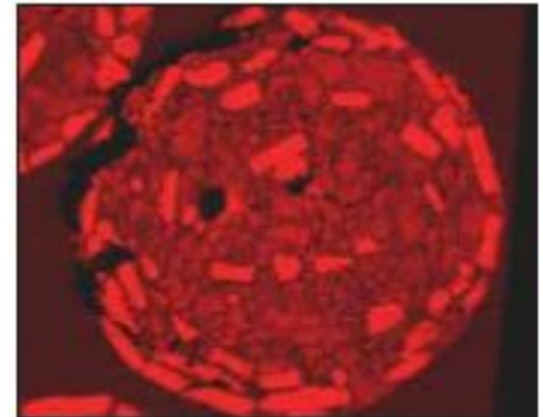
Backscattered electron image



C (EDS)



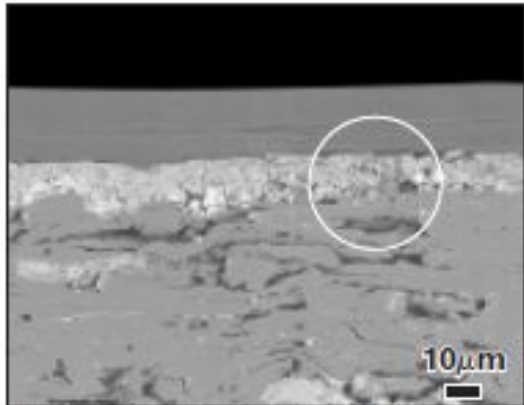
Na (EDS)



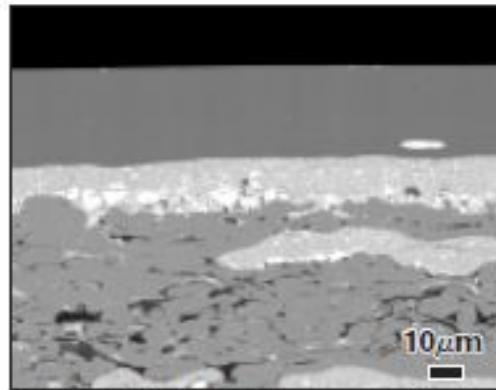
O (EDS)

Examples of SEM application

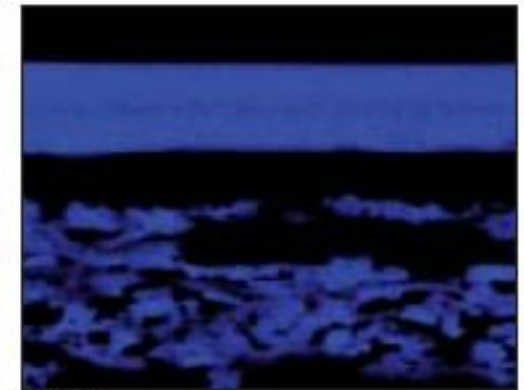
Paper Cross-section



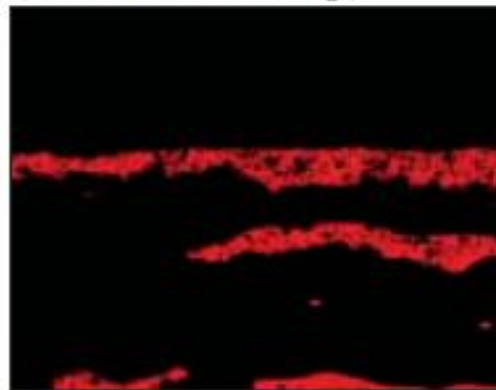
The cross section prepared with a razor edge often shows artifacts such as a loss of inorganic particles (shown in circle), or fibers being compressed.



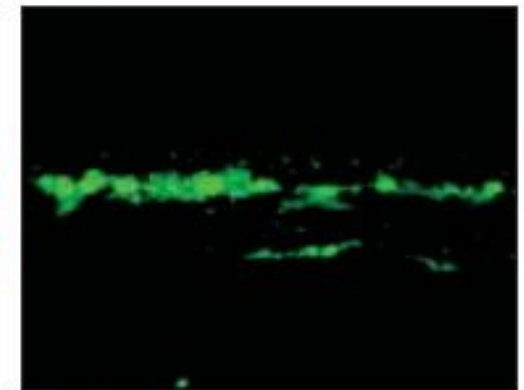
Cross section by the CP
(Backscattered electron image)



C (EDS)



Si (EDS)



Ca (EDS)



Evaporisation / sputtering

Is realised for covering the surface specimen by C, Au, Pt or Cu at high vacuum using special equipment.



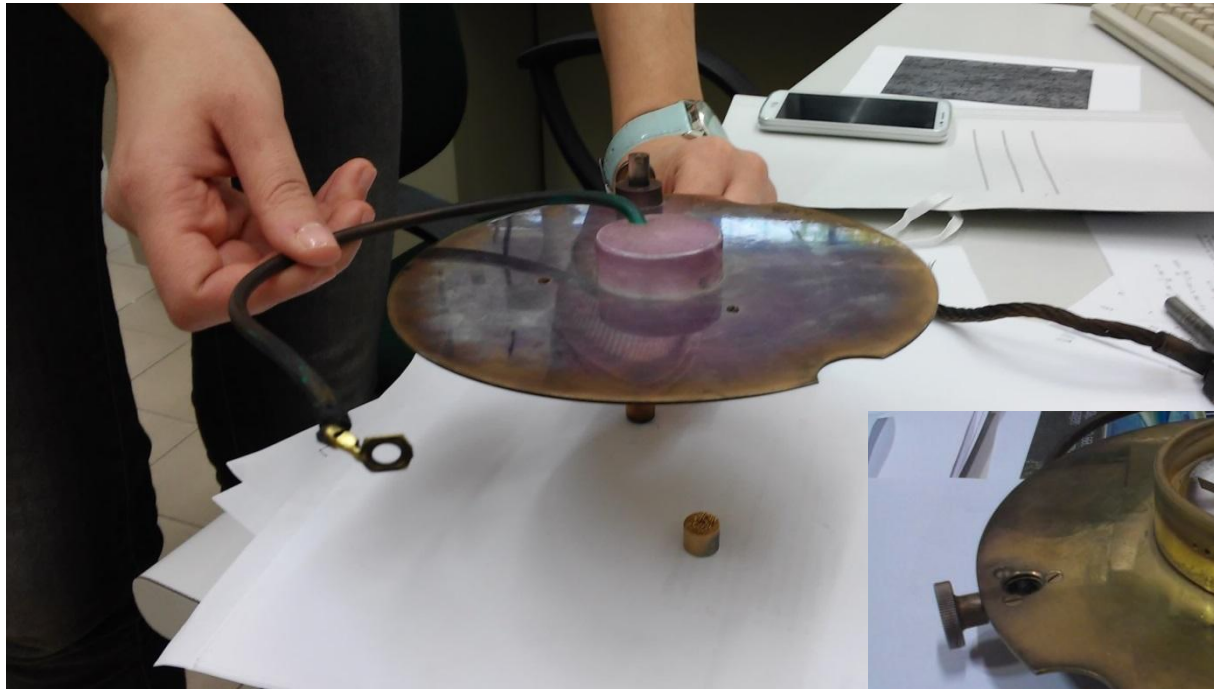


Evaporation





Cathode sputtering

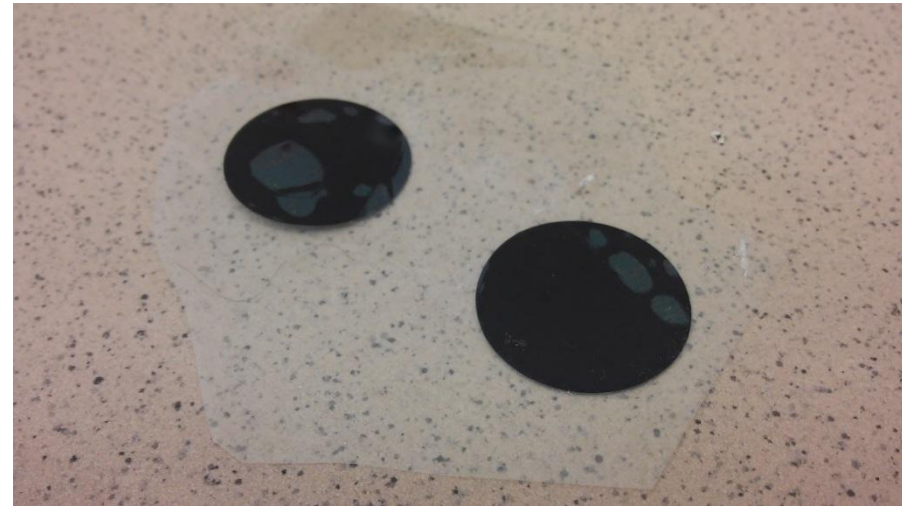




Specimen fixation



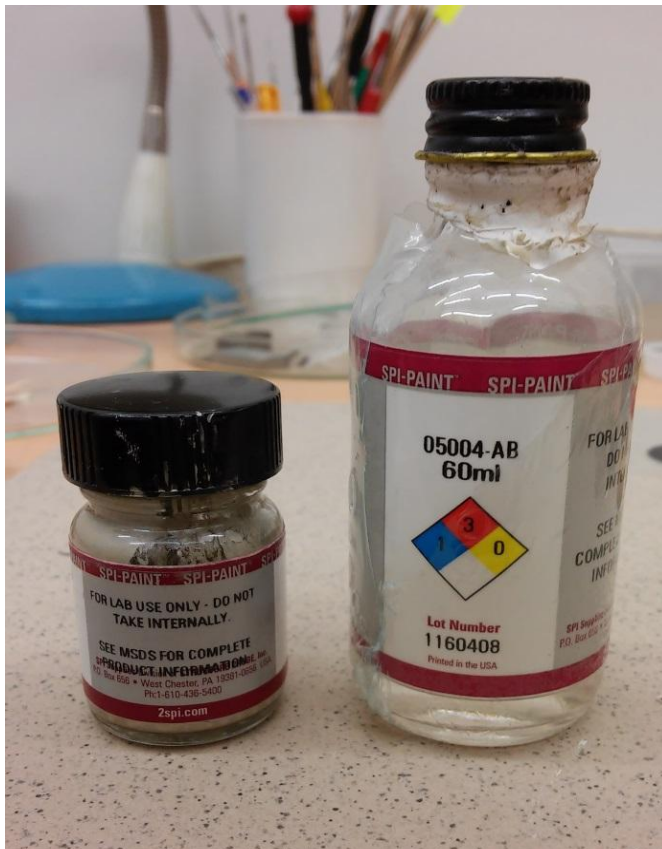
Current conductive
plasticine



Sticky carbon discs



Specimen fixation



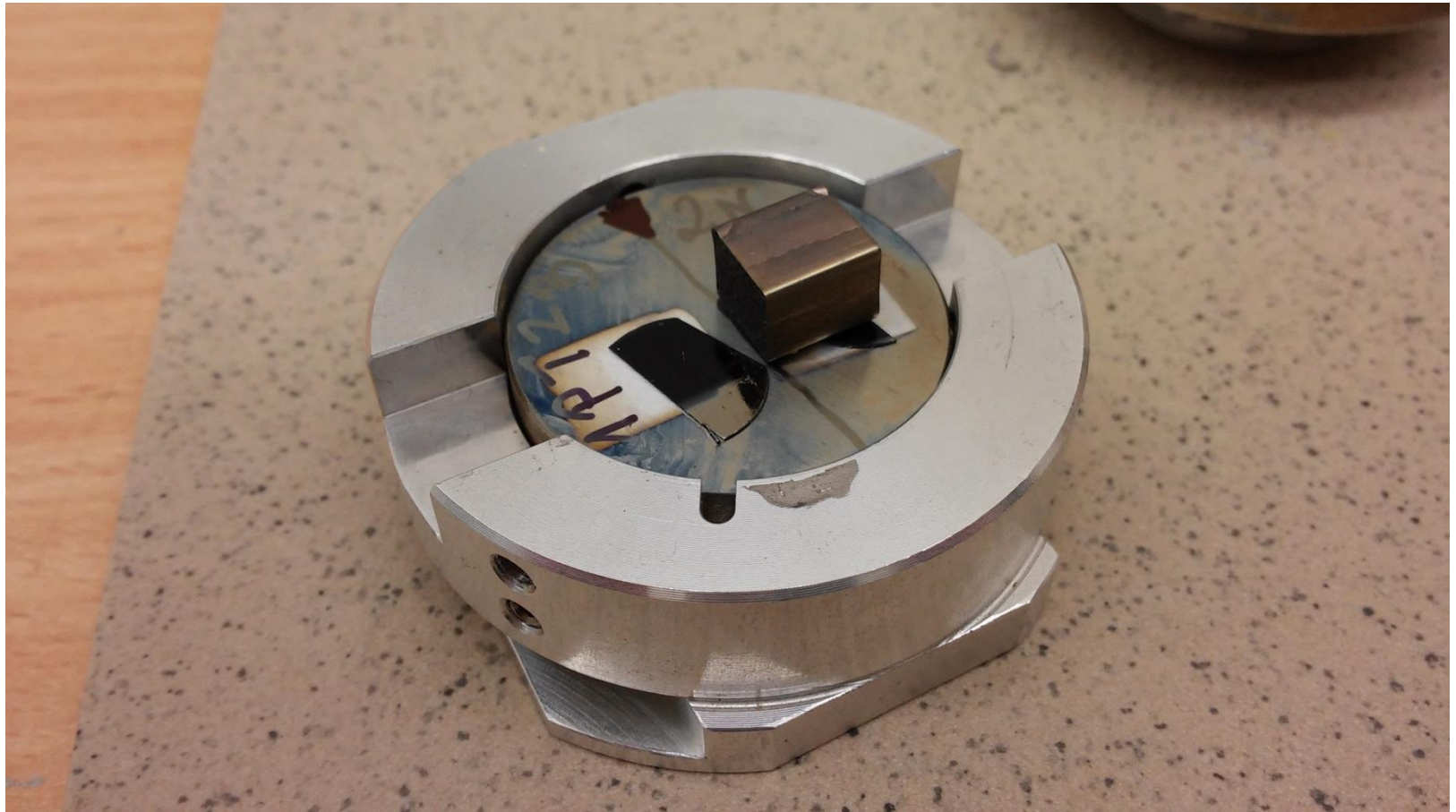
Silver glue



Double Scotch tape



Specimen fixed to the holder





Specimens inside the holder





Replica

The aim is to obtain direct microstructure of construction elements without their cutting or destruction.

Advantages:

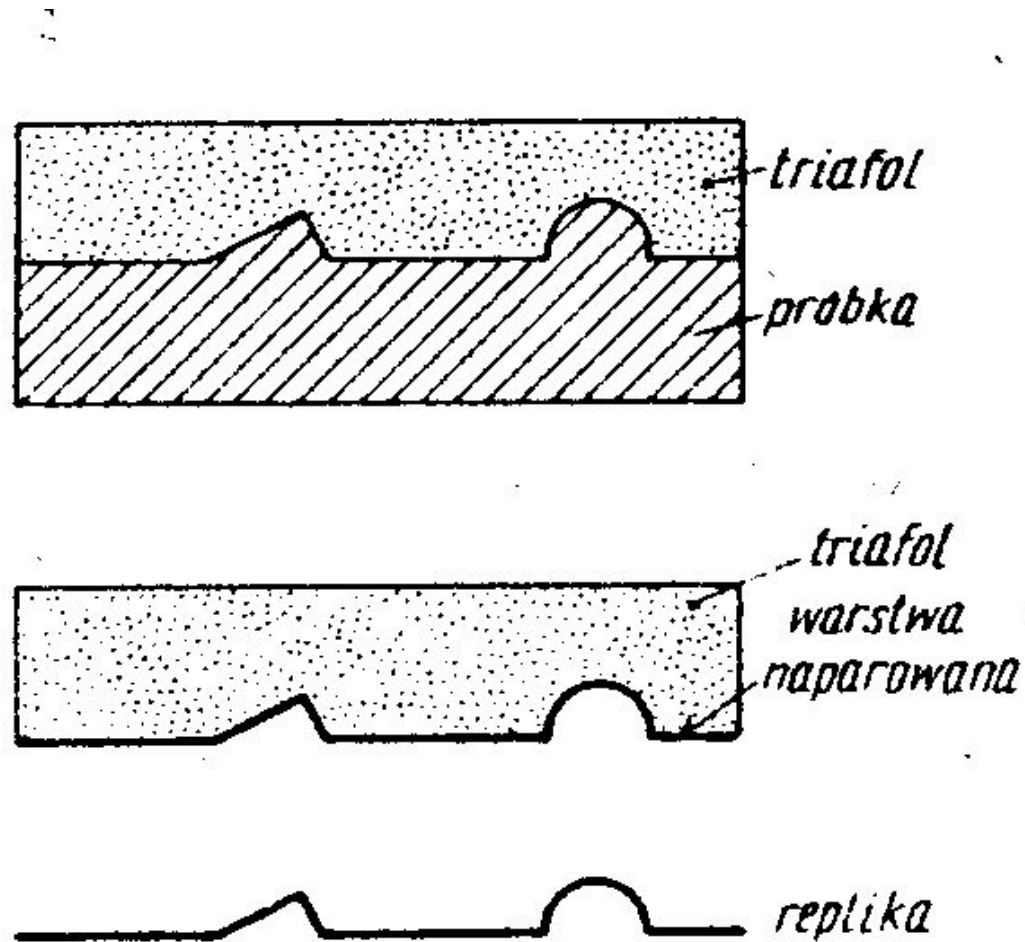
- Non destructive method (without decreasing the strength of investigated elements).

Disadvantages:

- The ability to study only the outer surface layer (cannot be representative for whole volume / thickness of investigated material).



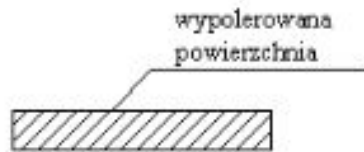
Replica



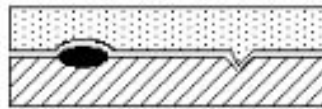


Replica

1a. Powierzchnia przygotowana do badań



2. Replika matrycowa nałożona na zgląd trawiony



3. Replika po zdjęciu ze zglądu



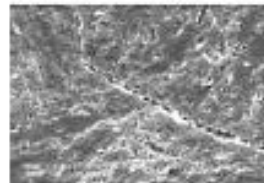
1b. Zgląd trawiony



4. Replika po napylenia w próżni warstwą zwiększającą kontrast



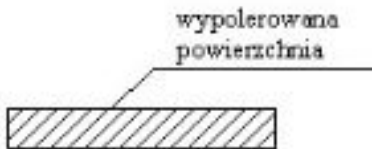
5. Obraz struktury obserwowany w skaningowym mikroskopie elektronowym





Extraction replica

1a. Zgląd nietrawiony



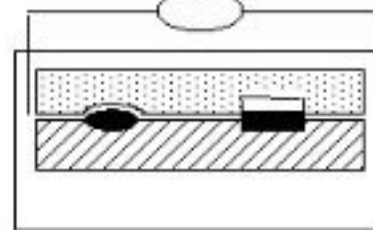
1b. Zgląd trawiony



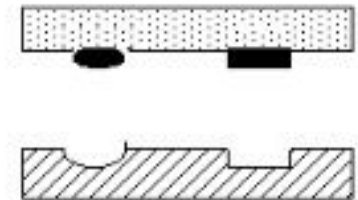
2. Replika nałożona na zgląd trawiony



3. Trawienie Elektrolityczne osnowy



4. Ekstrakcja wydzieli



5a. Replika napyłona w próżni do obserwacji w SEM

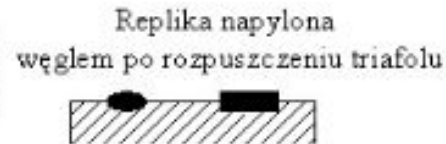


5a. Replika napyłona w węglu do obserwacji w TEM



6a. Obraz rozmieszczenia wydzieli obserwowany w SEM

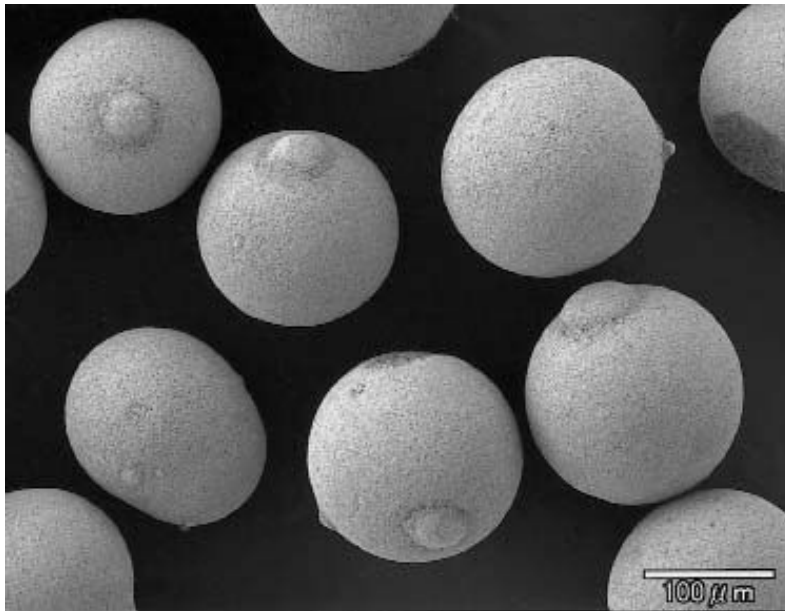
6b. Identyfikacja typów wydzieli w SEM



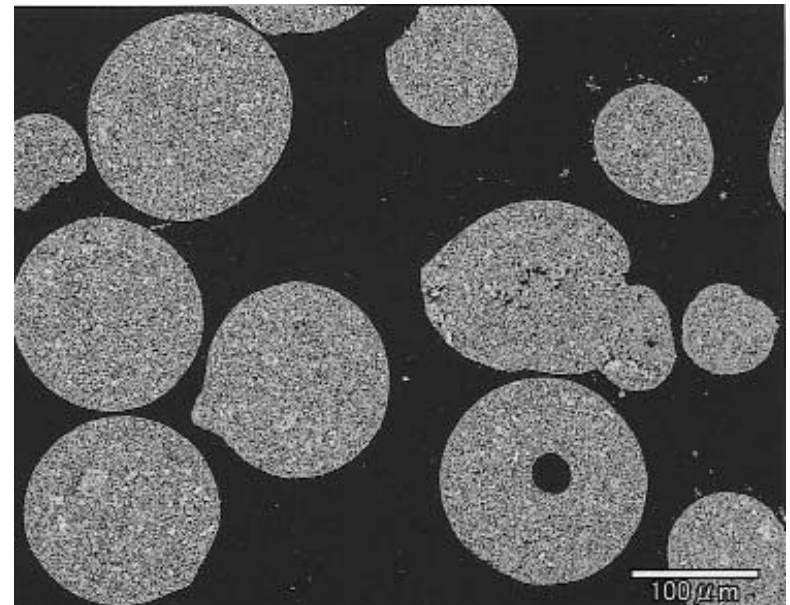


Examples

Surface of ceramic powder



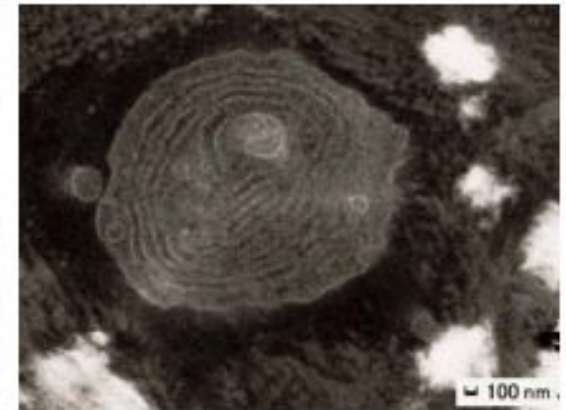
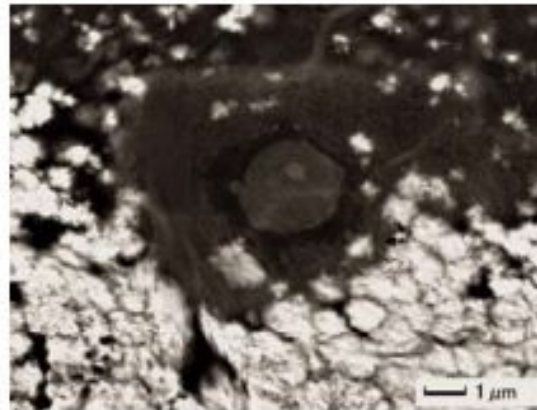
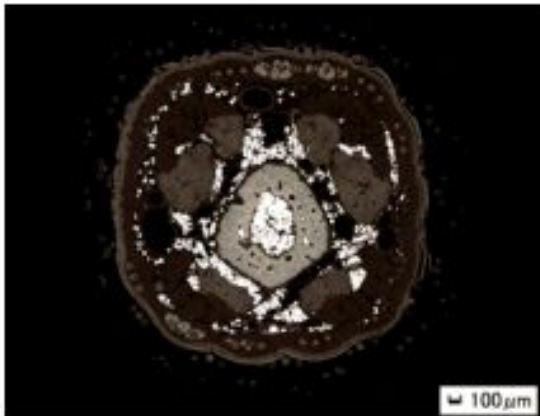
Cross section of ceramic powder



Examples

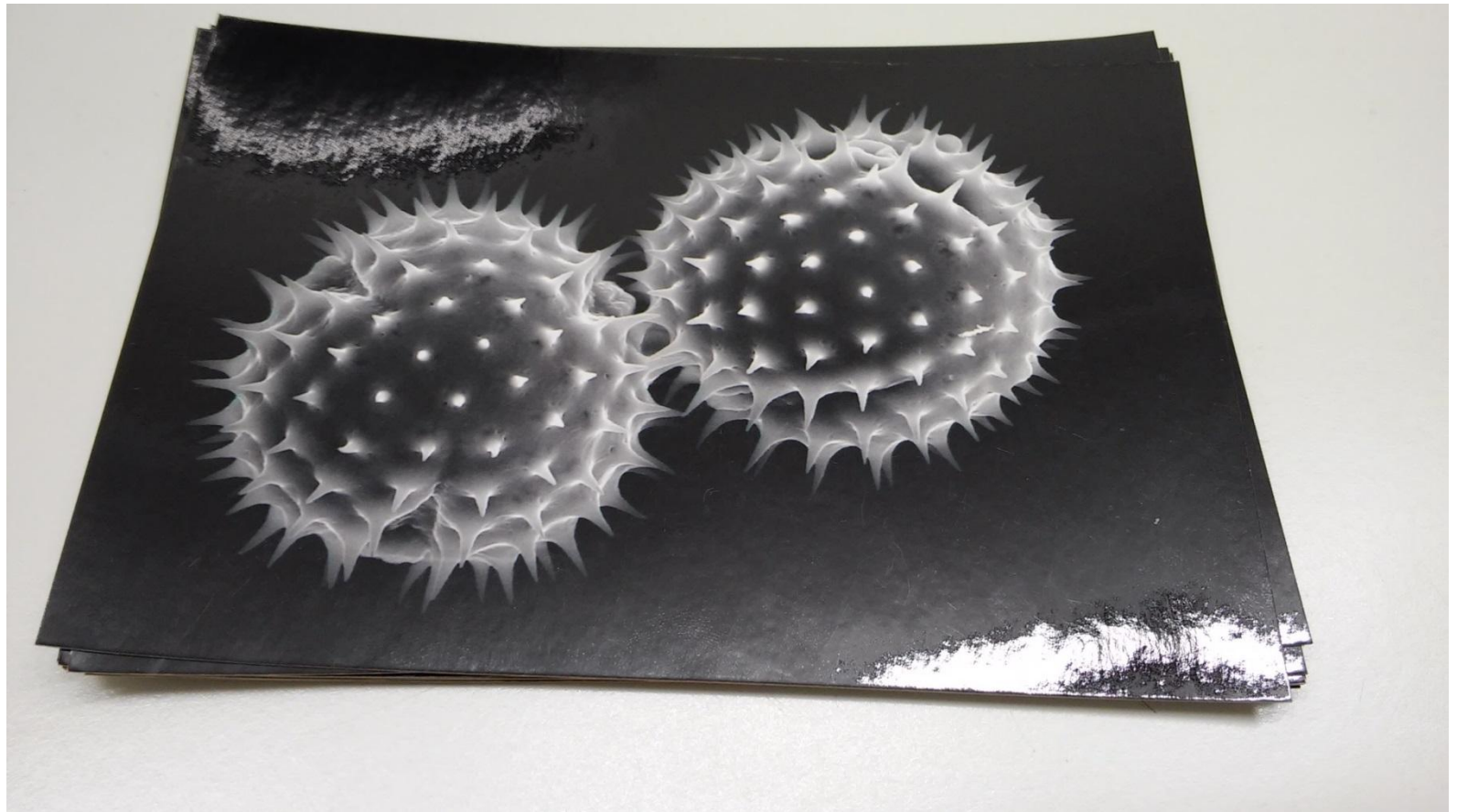
Cross section of bone

CP polishing





Pollen of flowers





Part of insect head





Brittle fracture





Composite

